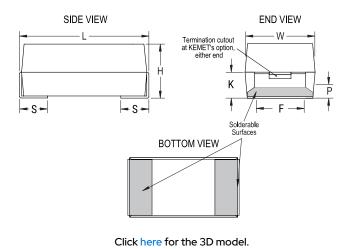


T497H157K006AT6110

T497 HRA, Tantalum, MnO2 Tantalum, HRA, 150 uF, 10%, 6.3 VDC, SMD, MnO2, Molded, High Reliability, Medical, N/A, 900 mOhms, 7238, 3.17 mm, 1.27 mm



General Information		
Series	T497 HRA	
Dielectric	MnO2 Tantalum	
Style	SMD Chip	
Description	SMD, MnO2, Molded, High Reliability, Medical	
Features	High Reliability, Medical	
RoHS	Yes	
Termination	Tin	
Qualifications	CWR09/19/29 Style	
AEC-Q200	No	
Typical Component Weight	349.01 mg	
Notes	Note: When solder coated terminations are required, add an additional 0.38mm (0.015inch) to the tolerances for "L", "W", "H", "K", "F" and "S".	
MSL	1	

150 uF

Standard Testing Only

10%

Dimensions	
L	7.24mm +/-0.38mm
W	3.81mm +/-0.38mm
Н	2.79mm +/-0.38mm
S	1.27mm +0.25/-0.13mm
F	3.68mm +0.13/-0.51mm
K	1.52mm MIN
Р	0.76mm MIN

Н	2.79mm +/-0.38mm	Voltage DC	6.3 VDC (85C), 4.22 VDC (125C
S	1.27mm +0.25/-0.13mm	Temperature Range	-55/+125°C
F	3.68mm +0.13/-0.51mm	Rated Temperature	85°C
K	1.52mm MIN	Humidity	85C, 85% RH, 1000 Hours, No Load
P 0.76mm MIN	0.76mm MIN		Load
		Dissipation Factor	10% 120Hz 25C
Packaging Specifications		Failure Rate	N/A
Packaging	T&R, 178mm	ESR	0.9 Ohms (100kHz 25C)
Packaging Quantity	500	Ripple Current	408 mA (rms, 100kHz 25C)
		Leakage Current	9.5 uA (5min 25°C)

Specifications Capacitance

Testing and Reliability

Tolerance

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.

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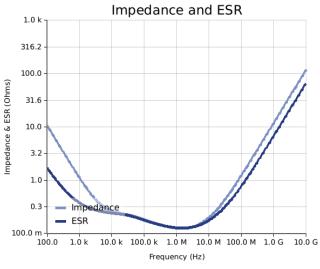


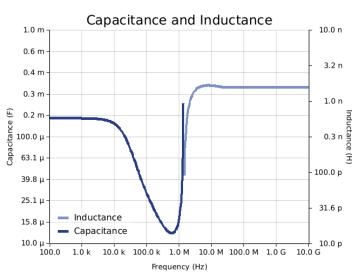
T497H157K006AT6110

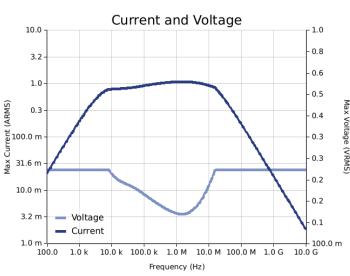
T497 HRA, Tantalum, MnO2 Tantalum, HRA, 150 uF, 10%, 6.3 VDC, SMD, MnO2, Molded, High Reliability, Medical, N/A, 900 mOhms, 7238, 3.17 mm, 1.27 mm

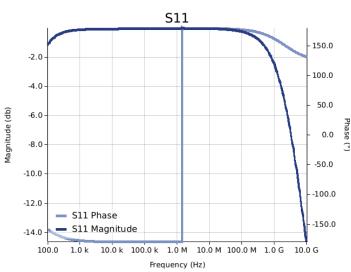
Simulations

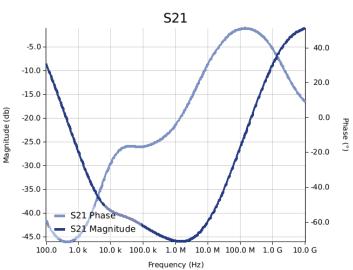
For the complete simulation environment please visit K-SIM.











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T497H157K006AT6110

T497 HRA, Tantalum, MnO2 Tantalum, HRA, 150 uF, 10%, 6.3 VDC, SMD, MnO2, Molded, High Reliability, Medical, N/A, 900 mOhms, 7238, 3.17 mm,

These are simulations.

This is not a specification!

The responses shown represent the typical response for each part type. Specific responses may vary, depending on manufacturing variation affects of all parameters involved, including the specified tolerances applied to capacitance and unspecified variations of ESR, ESL, and leakage resistance.

The responses shown do not represent a specified or implied maximum capability of the device for all applications.

- The ESR used for ripple "Ripple Current/Voltage vs. Frequency" plots is the ESR at ambient temperature.

- The ESR in the "Temperature Rise vs. Ripple Current" plots is adjusted to each incremental temperature rise before the power and ripple current is calculated.
 The effects shown herein are based on measured data from a multiple part sample of the parts in question.
 Ripple capability of this device will be factored by thermal resistance (Rth) created by circuit traces (addi affects of all parameters involved, including the specified tolerances applied to capacitance and unspecified variations of ESR, ESL, and leakage resistance.
 The peak voltages generated in the "Temperature Rise vs. Combined Ripple Currents" plot are calculated for each frequency and are not combined with voltages
- generated at any other harmonics.

 Please consult with the catalog or field applications engineer for maximum capability of the device in specific applications.

All product information and data (collectively, the "Information") are subject to change without notice.

KEMET K-SIM is designed to simulate behavior of components with respect to frequency, ambient temperature, and DC bias levels. The responses shown represent the typical response for each part type. Specific responses may vary, depending on manufacturing variation effects of all parameters involved, including the specified tolerances applied to capacitance and unspecified variations of ESR, ESL, and leakage resistance.

All Information given herein is believed to be accurate and reliable, but is presented without guarantee, warranty, or responsibility of any kind, expressed or implied. Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute – and we specifically disclaim – any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.

If you have any questions please contact K-SIM.

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